Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/652,138	TANAKA, KOICHIRO	
Examiner	Art Unit	
Zohreh A. Fay	1618	

SEARCHED						
Class	Subclass	Date	Examiner			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
The parent application was reviewed	8/30/2006	Z.F		
Inventor search	8/30/2006	Z.F		
Updated	11/7/2007	Z.F		
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